

December 2014

FDD86110

# N-Channel Shielded Gate PowerTrench<sup>®</sup> MOSFET 100 V, 50 A, 10.2 m $\Omega$

## Features

- Shielded Gate MOSFET Technology
- Max  $r_{DS(on)}$  = 10.2 m $\Omega$  at V<sub>GS</sub> = 10 V, I<sub>D</sub> = 12.5 A
- Max r<sub>DS(on)</sub> = 16 mΩ at V<sub>GS</sub> = 6 V, I<sub>D</sub> = 9.8 A
- 100% UIL tested
- RoHS Compliant

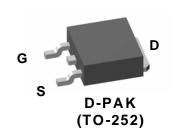


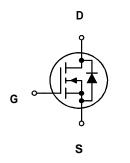
## **General Description**

This N-Channel MOSFET is produced using Fairchild Semiconductor's advanced PowerTrench<sup>®</sup> process that incorporates Shielded Gate technology. This process has been optimized for the on-state resistance and yet maintain superior switching performance.

## Application

DC - DC Conversion





## MOSFET Maximum Ratings T<sub>C</sub> = 25 °C unless otherwise noted

| Symbol                            | Param                                  | eter                   |           | Ratings     | Units |  |
|-----------------------------------|--|------------------------|-----------|-------------|-------|--|
| V <sub>DS</sub>                   | Drain to Source Voltage                |                        |           | 100         | V     |  |
| V <sub>GS</sub>                   | Gate to Source Voltage                 |                        |           | ±20         | V     |  |
|                                   | Drain Current -Continuous              | T <sub>C</sub> = 25 °C |           | 50          |       |  |
| I <sub>D</sub>                    | -Continuous                            | T <sub>A</sub> = 25 °C | (Note 1a) | 12.5        | Α     |  |
|                                   | -Pulsed                                |                        | (Note 4)  | 150         |       |  |
| E <sub>AS</sub>                   | Single Pulse Avalanche Energy          |                        | (Note 3)  | 135         | mJ    |  |
| P <sub>D</sub>                    | Power Dissipation                      | T <sub>C</sub> = 25 °C |           | 127         | w     |  |
|                                   | Power Dissipation                      | T <sub>A</sub> = 25 °C | (Note 1a) | 3.1         | VV    |  |
| T <sub>J</sub> , T <sub>STG</sub> | Operating and Storage Junction Tempera | iture Range            |           | -55 to +150 | °C    |  |

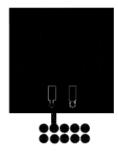
### **Thermal Characteristics**

| $R_{	ext{	heta}JC}$ | Thermal Resistance, Junction to Case             | 0.98 | °C/W |
|---------------------|--|------|------|
| $R_{\theta JA}$     | Thermal Resistance, Junction to Ambient (Note 1a | ) 40 | 0/10 |

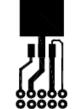
## Package Marking and Ordering Information

| Device Marking | Device   | Package       | Reel Size | Tape Width | Quantity   |
|----------------|----------|---------------|-----------|------------|------------|
| FDD86110       | FDD86110 | D-PAK(TO-252) | 13 "      | 12 mm      | 2500 units |

| Symbol                               | Parameter  | Test Conditions   | Min     | Тур         | Max         | Units    |
|--------------------------------------|--|---|---------|-------------|-------------|----------|
|                                      | cteristics   |   |         | 71          |             |          |
| BV <sub>DSS</sub>                    | Drain to Source Breakdown Voltage                    | I <sub>D</sub> = 250 μA, V <sub>GS</sub> = 0 V  | 100     |             |             | V        |
| ∆BV <sub>DSS</sub>                   | Breakdown Voltage Temperature                        |   | 100     |             |             |          |
| $\Delta T_{J}$                       | Coefficient  | $I_D = 250 \ \mu\text{A}$ , referenced to 25 °C   |         | 72          |             | mV/°C    |
| IDSS                                 | Zero Gate Voltage Drain Current                      | V <sub>DS</sub> = 80 V, V <sub>GS</sub> = 0 V   |         |             | 1           | μA       |
| I <sub>GSS</sub>                     | Gate to Source Leakage Current                       | $V_{GS} = \pm 20 \text{ V}, V_{DS} = 0 \text{ V}$   |         |             | ±100        | nA       |
| On Chara                             | cteristics   |   |         |             |             |          |
| V <sub>GS(th)</sub>                  | Gate to Source Threshold Voltage                     | V <sub>GS</sub> = V <sub>DS</sub> , I <sub>D</sub> = 250 μA                                 | 2       | 2.8         | 4           | V        |
| $\Delta V_{GS(th)}$                  | Gate to Source Threshold Voltage                     |   |         | 40          |             |          |
| $\Delta T_J$                         | Temperature Coefficient                              | $I_D = 250 \ \mu$ A, referenced to 25 °C  |         | -10         |             | mV/°C    |
|                                      | Static Drain to Source On Resistance                 | V <sub>GS</sub> = 10 V, I <sub>D</sub> = 12.5 A   |         | 8.5         | 10.2        |          |
| r <sub>DS(on)</sub>                  |  | $V_{GS} = 6 V, I_D = 9.8 A$   | 11.3 16 |             | 16          | mΩ       |
|                                      |  | $V_{GS} = 10 \text{ V}, \text{ I}_{D} = 12.5 \text{ A}, \text{T}_{J} = 125^{\circ}\text{C}$ |         | 15          | 18          |          |
| 9fs                                  | Forward Transconductance                             | $V_{DS} = 10 \text{ V}, \text{ I}_{D} = 12.5 \text{ A}$                                     |         | 38          |             | S        |
| C <sub>iss</sub><br>C <sub>oss</sub> | Characteristics Input Capacitance Output Capacitance | −−− V <sub>DS</sub> = 50 V, V <sub>GS</sub> = 0 V,<br>f = 1MHz                              |         | 1702<br>379 | 2265<br>505 | pF<br>pF |
| C <sub>rss</sub>                     | Reverse Transfer Capacitance                         |   |         | 17          | 30          | pF       |
| R <sub>g</sub>                       | Gate Resistance                                      |   | 0.1     | 0.5         | 1.5         | Ω        |
| Switching                            | Characteristics                                      |   |         |             |             |          |
| t <sub>d(on)</sub>                   | Turn-On Delay Time                                   |   |         | 12          | 20          | ns       |
| t <sub>r</sub>                       | Rise Time  | V <sub>DD</sub> = 50 V, I <sub>D</sub> = 12.5 A,  |         | 5.4         | 10          | ns       |
| t <sub>d(off)</sub>                  | Turn-Off Delay Time                                  | $V_{GS} = 10 \text{ V}, \text{ R}_{GEN} = 6 \Omega$   |         | 19          | 35          | ns       |
| t <sub>f</sub>                       | Fall Time  |   |         | 3.9         | 10          | ns       |
| Q <sub>g</sub>                       | Total Gate Charge                                    | $V_{GS} = 0 \text{ V to } 10 \text{ V}$ V <sub>DD</sub> = 50 V,                             |         | 25          | 35          | nC       |
| Q <sub>gs</sub>                      | Gate to Source Charge                                | V <sub>DD</sub> = 50 V,<br>I <sub>D</sub> = 12.5 A  |         | 7.1         |             | nC       |
| Q <sub>gd</sub>                      | Gate to Drain "Miller" Charge                        |   |         | 5.2         |             | nC       |
|                                      | Irce Diode Characteristics                           |   |         |             |             | I        |
|                                      |  | 1/ - 0/1 - 125 (Note 0)   |         | 0.90        | 1.0         | 17       |
| V <sub>SD</sub>                      | Source-Drain Diode Forward Voltage                   | $V_{GS} = 0 V, I_S = 12.5 A$ (Note 2)   |         | 0.80        | 1.3         | V        |
|                                      |  | $V_{GS} = 0 V, I_S = 2.6 A$ (Note 2)  |         | 0.72        | 1.2         |          |
| t <sub>rr</sub>                      | Reverse Recovery Time                                | I <sub>F</sub> = 12.5 A, di/dt = 100 A/μs   |         | 52<br>60    | 83          | ns       |
| Q <sub>rr</sub>                      | Reverse Recovery Charge                              |   |         | 60          | 96          | nC       |



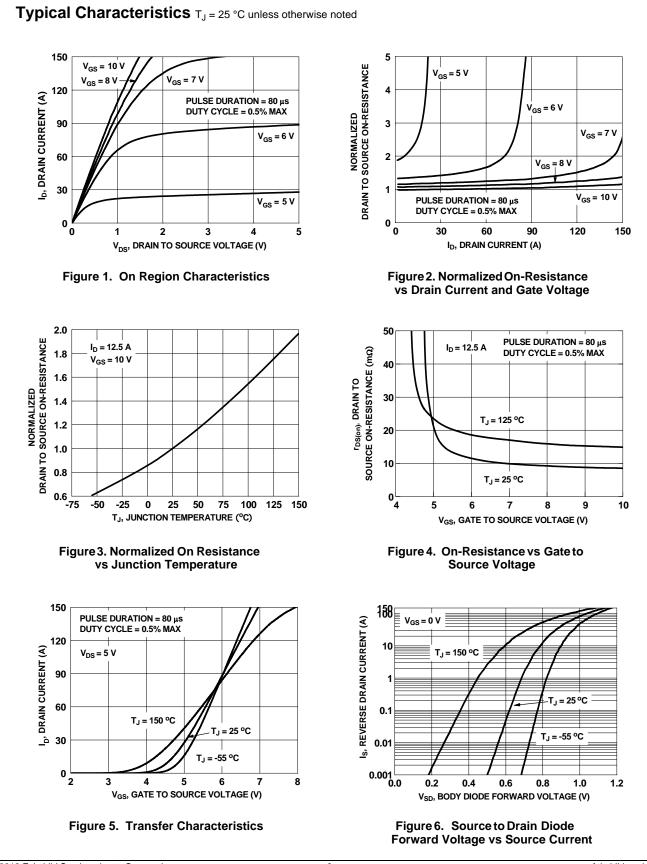
a) 40 °C/W when mounted on a 1 in<sup>2</sup> pad of 2 oz copper

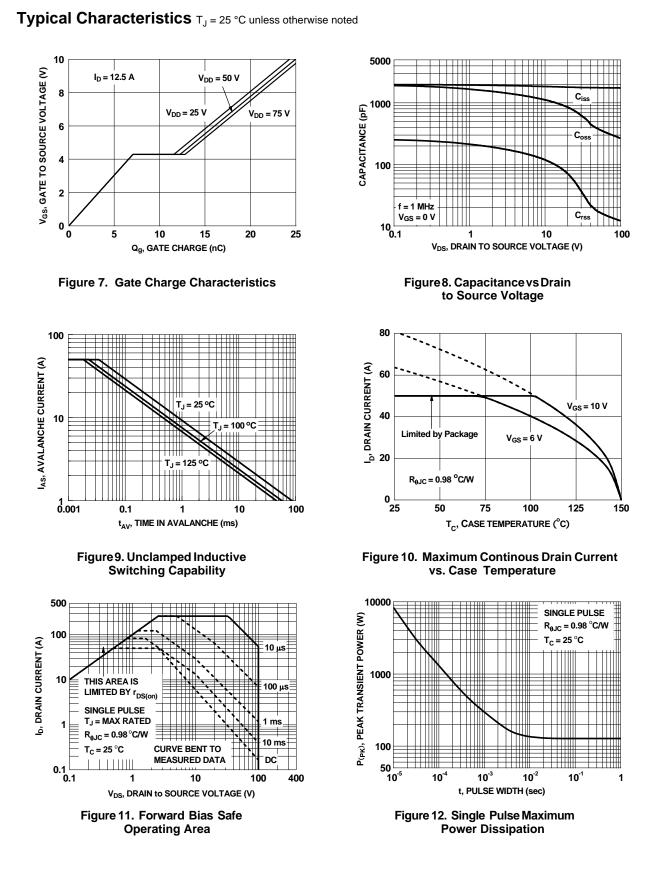


b) 96 °C/W when mounted on a minimum pad

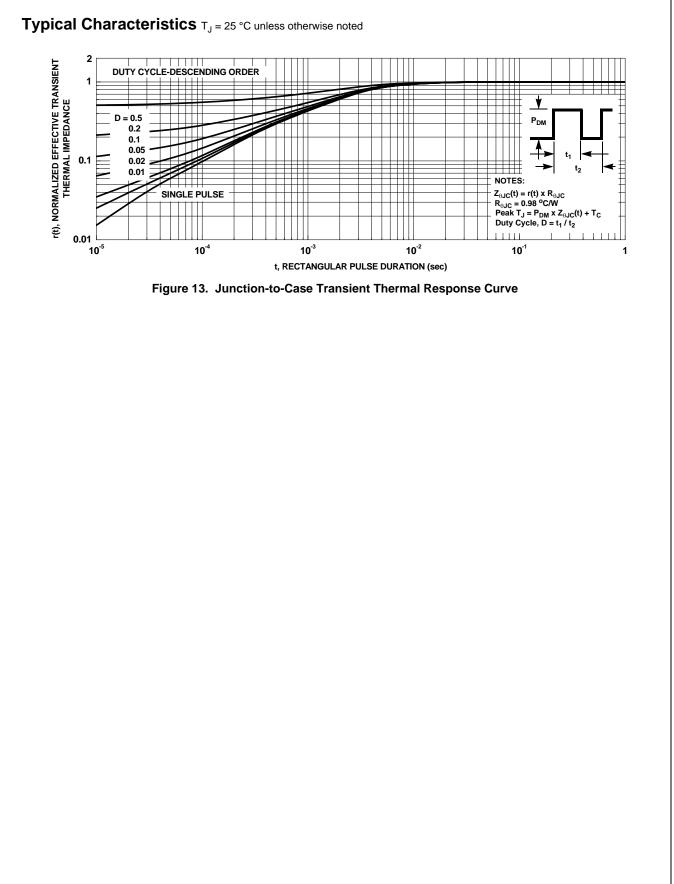
- Pulse Test: Pulse Width < 300 µs, Duty cycle < 2.0%.</li>
   Starting T<sub>J</sub> = 25 °C, L = 0.3 mH, I<sub>AS</sub> = 30 A, V<sub>DD</sub> = 90 V, V<sub>GS</sub> = 10 V. 100% test at L = 0.1 mH, I<sub>AS</sub> = 48 A.
   Pulsed Drain current is tested at 300 µs with 2% duty cycle. For repetitive pulses, the pulse width is limited by the maximum junction temperature.

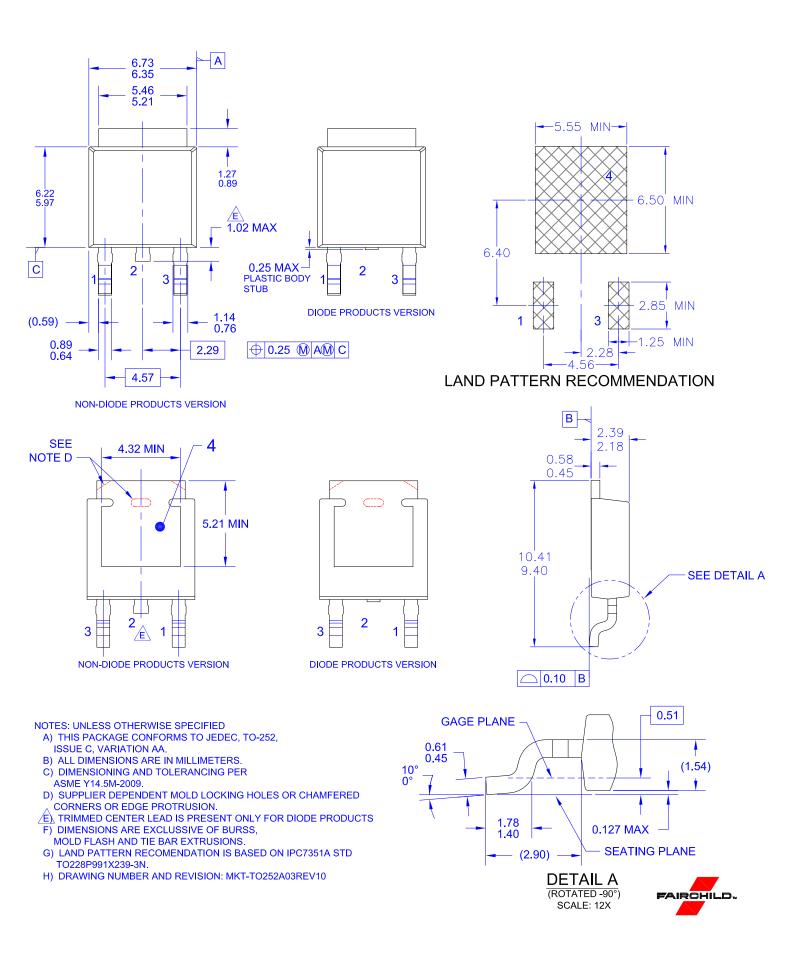


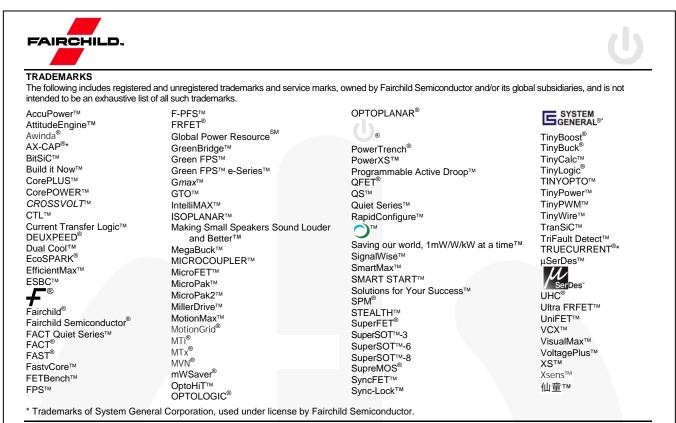




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